|  |  |
| --- | --- |
|  | WIPO |
| IPC/WG/35/INF/1 Prov. | |
| ORIGINAL : français/english | |
| DATE : 11 avril 2016/april 11, 2016 | |

**Union particulière pour la classification internationale des brevets (Union de l’IPC)**

**Groupe de travail sur la révision de la CIB**

**Trente‑cinquième session**

**Genève, 11 – 15 avril 2016**

**Special Union for the International Patent Classification**

**(IPC Union)**

**IPC Revision Working Group**

**Thirty-Fifth Session**

**Geneva, April 11 to 15, 2016**

# LISTE PROVISOIRE[[1]](#footnote-2)\* DES PARTICIPANTS/

# PROVISIONAL LIST[[2]](#footnote-3)\* OF PARTICIPANTS

*établie par le Secrétariat/*

*prepared by the Secretariat*

## I. ÉTATS MEMBRES/MEMBER STATES

### ALLEMAGNE/GERMANY

Michael MAURUS, Senior Patent Examiner, Classification Systems Section, German Patent and Trade Mark Office, Munich

Thomas SCHENK, Senior Patent Examiner, Classification Systems Section, German Patent and Trade Mark Office, Munich

Florian SIEBEL, Senior Patent Examiner, Classification Systems Section, German Patent and Trade Mark Office, Munich

Oliver STEINKELLNER, IPC Expert, Classification Systems Section, German Patent and Trade Mark Office, Munich

### AUSTRALIE/AUSTRALIA

Thanh NGUYEN (Ms.), Classification Coordinator, IP Australia, Department of Industry, Innovation and Science, Canberra

### CANADA

Nancy BEAUCHEMIN (Mme), gestionnaire de programme - International, Direction des brevets, Office de la propriété intellectuelle du Canada, Gatineau

### CHINE/CHINA

XIAO Li (Ms.), Project Officer, Patent Documentation Department, State Intellectual Property Office of the People’s Republic of China (SIPO), Beijing

JIA Yujie (Ms.), Classifier, China Patent Development Corporation, State Intellectual Property Office of the People’s Republic of China (SIPO), Beijing

SHI Hui (Ms.), Patent Examiner, Classifier, China Patent Development Corporation, State Intellectual Property Office of the People’s Republic of China (SIPO), Beijing

### ÉGYPTE/EGYPT

Nabila Mohamed Mahmoud MEKKY (Ms.), General Manager, Technical Examination, Technical Patent Examination Office, Academy of Scientific Research and Technology, Cairo

### ESPAGNE/SPAIN

Elena PINA (Sra.), Técnica Superior Examinadora de Patentes, Oficina Española de Patentes y Marcas, Ministerio de Industria, Energía y Turismo, Madrid

### ÉTATS-UNIS D'AMÉRIQUE/UNITED STATES OF AMERICA

William BREWSTER, Supervisory Patent Classifier, Classification Standards and Development Division, United States Department of Commerce, United States Patent and Trademark Office (USPTO), Alexandria

Matthew BROOKS, Supervisory Patent Classifier, Classification Standards and Development, Office of International Patent Cooperation, United States Department of Commerce, United States Patent and Trademark Office (USPTO), Alexandria

John RUGGLES, Patent Classifier, Classification Standards and Development, Office of International Patent Cooperation, United States Department of Commerce, United States Patent and Trademark Office (USPTO), Alexandria

### FÉDÉRATION DE RUSSIE/RUSSIAN FEDERATION

Andrey SHPIKALOV, Senior Researcher, Federal Institute of Industrial Property, Federal Service for Intellectual Property (ROSPATENT), Moscow

### FRANCE

Tristan IMBERT, expert électricité, Département des brevets, Institut national de la propriété industrielle (INPI), Courbevoie

Philippe MARCEL, expert en chimie, Département des brevets, Institute national de la propriété industrielle (INPI), Courbevoie

Magalie MATHON (Mme), expert en mécanique, Département des brevets, Institute national de la propriété industrielle (INPI), Courbevoie

### IRLANDE/IRELAND

Fergal BRADY, Senior Patent Examiner, Patent Examination, Patents Office, Department of Jobs, Enterprise and Innovation, Kilkenny

### JAPON/JAPAN

Masakazu SHIOZAWA, Deputy Director, Patent Classification Policy Planning Section, Administrative Affairs Division, Japan Patent Office (JPO), Tokyo

Yuki AKASAKA, Classification Project Coordinator (Physics), Patent Classification Policy Planning Section, Administrative Affairs Division, Japan Patent Office (JPO), Tokyo

Hiroaki ISHIZAKA, Classification Project Coordinator (Electricity), Patent Classification Policy Planning Section, Administrative Affairs Division, Japan Patent Office (JPO), Tokyo

YAZAWA SHUICHIRO, Classification Project Coordinator (Machinery), Patent Classification Policy Planning Section, Administrative Affairs Division, Japan Patent Office (JPO), Tokyo

Keisuke TSUCHIHASHI, Classification Project Coordinator (Chemistry), Patent Classification Policy Planning Section, Administrative Affairs Division, Japan Patent Office (JPO), Tokyo

### MEXIQUE/MEXICO

Pablo ZENTENO MÁRQUEZ, Especialista en Propiedad Industrial A, Dirección Divisional de Patentes, Instituto Mexicano de la Propiedad Industrial (IMPI), Mexico

### NORVÈGE/NORWAY

Bjørn TISTHAMMER, Senior Examiner, Patent Department, Norwegian Industrial Property Office, Oslo

### RÉPUBLIQUE DE CORÉE/REPUBLIC OF KOREA

LEE Eunkyu, Deputy Director, Energy Technology Examination Division, Korean Intellectual Property Office (KIPO), Daejeon

JEONG Chi-Yeong, Assistant Deputy Director, Korean Intellectual Property Office (KIPO) Daejeon

LEE Yun-Seok, Assistant Manager, IPC Revision, Patent Information Promotion Center (PIPC), Daejeon

JUNG Byung-Te, Assistant Manager, IPC Revision, Patent Information Promotion Center (PIPC), Daejeon

### ROUMANIE/ROMANIA

Diana NITA (Ms.), Patent Examiner, Patent Department, State Office for Inventions and Trademarks (OSIRM), Bucharest

### ROYAUME-UNI/UNITED KINGDOM

Matthew LAWSON, Senior Patent Examiner, Patents Division, UK Intellectual Property Office, Newport

Bill THOMSON, Senior Patent Examiner, Patents Division, UK Intellectual Property Office, Newport

William RIGGS, Patent Examiner, Patents Division, UK Intellectual Property Office, Newport

### SERBIE/SERBIA

Milan MILJEVIĆ, Patent Examiner, Belgrade

### SUÈDE/SWEDEN

Anders BRUUN, Patent Expert, Swedish Patent and Registration Office, Stockholm

### SUISSE/SWITZERLAND

Pascal WEIBEL, chef Examen, Division des brevets, Institut fédéral de la propriété intellectuelle, Berne

François LOISEAU, expert en brevet, Division des brevets, Institut fédéral de la propriété intellectuelle, Berne

Philippe TATASCIORE, expert en brevet, Division des brevets, Institut fédéral de la propriété intellectuelle, Berne

### TURQUIE/TURKEY

Atalay Berk DAMGACIOGLU, Patent Examiner, Patent Department, Turkish Patent Institute, Ankara

### UKRAINE

Vladyslav HAPOCHKA, Chief Expert, Division of Physics-Chemical Technologies, Ministry of Economic Development and Trade of Ukraine, State Intellectual Property Service of Ukraine, State Enterprise, Kyiv

Vladyslava POPKO (Ms.), Chief Expert, Division of Building and Mining, Ministry of Economic Development and Trade of Ukraine, State Intellectual Property Service of Ukraine, State Enterprise, Kyiv

## II. ORGANISATIONS MEMBRES/MEMBER ORGANIZATIONS

### ORGANISATION AFRICAINE DE LA PROPRIÉTÉ INTELLECTUELLE (OAPI)/AFRICAN INTELLECTUAL PROPERTY ORGANIZATION (OAPI)

Idrissa CISSOKO, examinateur en mécanique, Yaoundé

### ORGANISATION EUROPÉENNE DES BREVETS (OEB)/EUROPEAN PATENT ORGANISATION (EPO)

Roberto IASEVOLI, Head, Classification Board, Classification Knowledge Department, Rijswijk

Maarten ALINK, Classification Board Member Mechanics, Classification, Munich

Sandrine AUBARD (Ms.), Classification Board Member, Munich

Christian KÖNIGSTEIN, Classification Board Member Electricity, Classification, Rijswijk

Pieter NIEUWENHUIS, Classification Board Member, Munich

Ingo SEELMANN, Classification Board Member, Munich

Jérôme TERRIER DE LA CHAISE, Classification Board Member, Rijswijk

## III. BUREAU/OFFICERS

président/Chair: Oliver STEINKELLNER (ALLEMAGNE/GERMANY)

vice-président/ Bjørn TISTHAMMER (NORVÈGE/NORWAY)  
Vice-Chair:

secrétaire/Secretary: XU Ning (Mme/Mrs.) (OMPI/WIPO)

## IV. BUREAU INTERNATIONAL DE L’ORGANISATION MONDIALE DE LA PROPRIÉTÉ INTELLECTUELLE (OMPI)/ INTERNATIONAL BUREAU OF THE WORLD INTELLECTUAL PROPERTY ORGANIZATION (WIPO)

Antonios FARASSOPOULOS, directeur de la Division des classifications internationales et des normes/Director, International Classifications and Standards Division

Patrick FIÉVET, chef de la Section des systèmes informatiques, Division des classifications internationales et des normes, Secteur de l’infrastructure mondiale/Head, IT Systems Section, International Classifications and Standards Division, Global Infrastructure Sector

XU Ning (Mme/Mrs.), chef de la Section de la classification internationale des brevets (CIB), Division des classifications internationales et des normes, Secteur de l’infrastructure mondiale/  
Head, International Patent Classification (IPC) Section, International Classifications and Standards Division, Global Infrastructure Sector

Rastislav MARČOK, administrateur principal de la classification des brevets de la Section de la classification internationale des brevets (CIB), Division des classifications internationales et des normes, Secteur de l’infrastructure mondiale/Senior Patent Classification Officer, International Patent Classification (IPC) Section, International Classifications and Standards Division, Global Infrastructure Sector

Isabelle MALANGA SALAZAR (Mme/Mrs.), assistante à l’information de la Section de la classification internationale des brevets (CIB), Division des classifications internationales et des normes, Secteur de l’infrastructure mondiale/Information Assistant, International Patent Classification (IPC) Section, International Classifications and Standards Division, Global Infrastructure Sector

[Fin du document]

End of document]

1. \* Les participants sont priés d’informer le Secrétariat, en modifiant la présente liste provisoire, des modifications qui devraient être prises en considération lors de l’établissement de la liste finale des participants. [↑](#footnote-ref-2)
2. \* Participants are requested to inform the Secretariat of any changes which should be taken into account in preparing the final list of participants. Changes should be requested by making corrections on the present provisional list. [↑](#footnote-ref-3)